## Notice of References Cited 10/550,009 Reexamination CHEN ET AL. Examiner Arishar 571-272-7796 Reexamination CHEN ET AL. Page 1 of 1

Application/Control No.

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-H0,002,051	11-2002	Zhu et al.	370/395.21
*	В	US-2006/0274706	12-2006	Chen et al.	370/340
*	С	US-2001/0041575	11-2001	AMIRIJOO et al.	455/456
*	D	US-2003/0021256	01-2003	Lee, Jung-Sup	370/342
*	E	US-7,181,209	02-2007	Tamura, Toshiyuki	455/432.1
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	Ŀ	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N			•		
	0					
	Р					·
1.77	Q					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
,	U	
	>	
	w	•
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Applicant(s)/Patent Under